Search Notes			

Application/Control No.	Applicant(s)/Patent unde Reexamination	er
10/748,168	KIM ET AL.	
Examiner	Art Unit	
Yuwen Pan	2682	

	SEAR	CHED	
Class	Subclass	Date	Examiner
455	436,437,4 44,41.2	1/3/2005	ΥP
370	331		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH N (INCLUDING SEARC	H STRATEGY)
	DATE	EXMR
EAST (USPG-PUB,USPAT)	1/3/2005	YP
		<u> </u>